

Notice of References Cited

Application/Control No.

09/699,894

Applicant(s)/Patent Under

Reexamination

PADMANABHAN ET AL.

Examiner

Daniel A. Nolan

Art Unit

2655

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-6,108,628	08-2000	Komori et al.	704/238
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NON-PATENT DOCUMENTS

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	U	Chittineni et al ("On the Maximization of Divergence in Pattern Recognition - Correspondence", IEEE Transactions on Information Theory, September 1976)
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	W	Wang et al ("Classification Of Discrete Data With Feature Space Transformation", IEEE Transactions on Automatic Control, June 1979)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.